

Test:

Channel 1 - 2

Automatic

1 V
2 V
5 V
10 V

Very Low Frk.
Low 2 Frk.
Lov 1 Frk.
Test Frk.
H Frk (5-10V)

L. Current (47K)
M. Current (2K7)
H. Current (550)

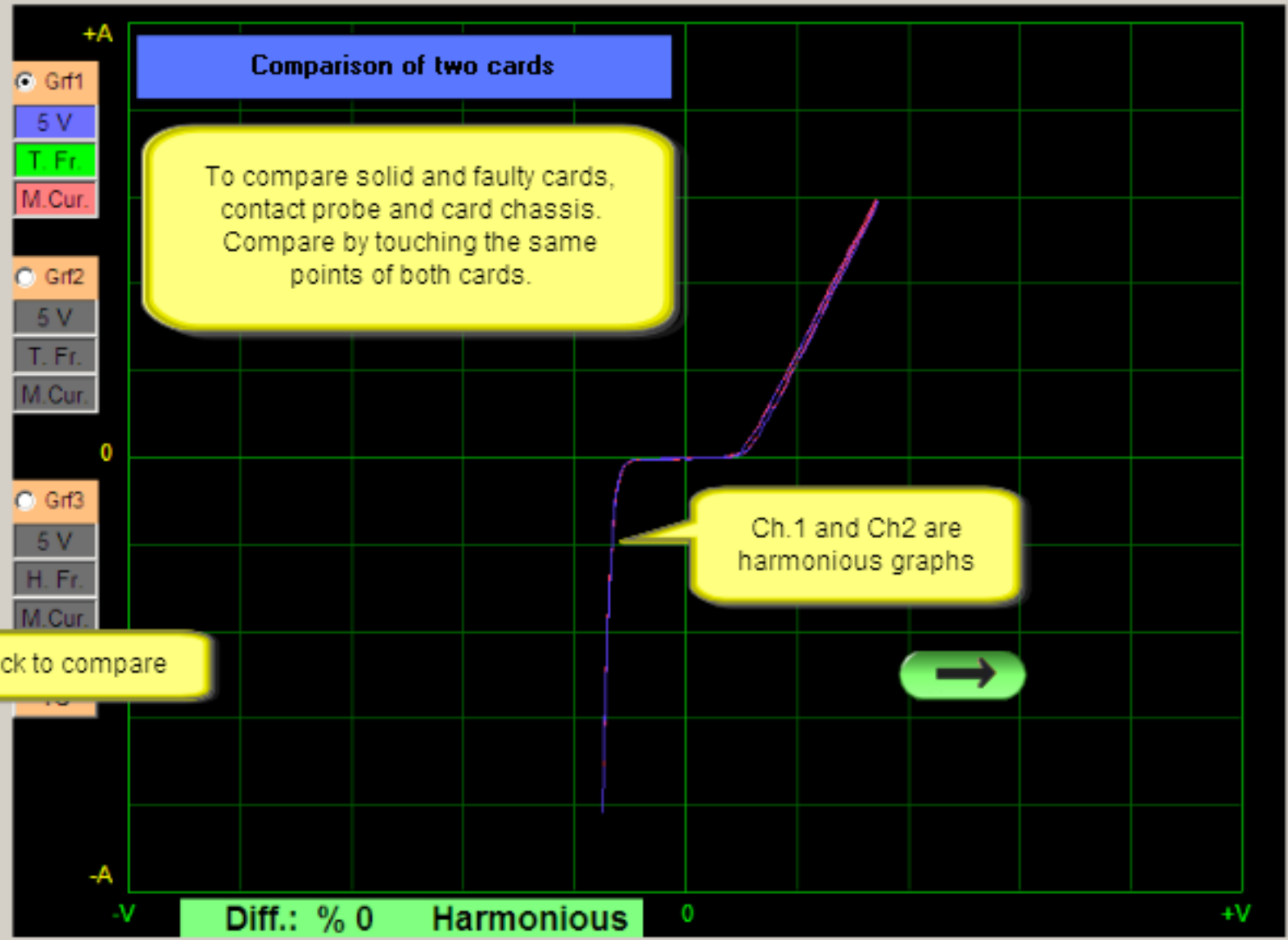
Compare
 Capasite Test
 T.T.T. FET IGBT

Click to compare

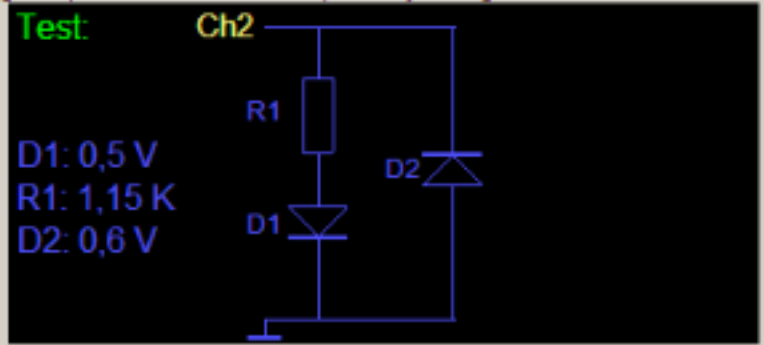
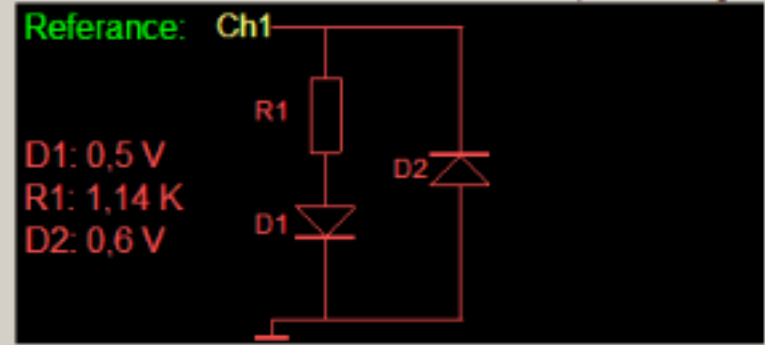
Memory Save - Test

Recording

Tolerance (%) **3**



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.



OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

Test:

Channel 1 - 2

Automatic

1 V
2 V
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10 V

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H Frk (5-10V)

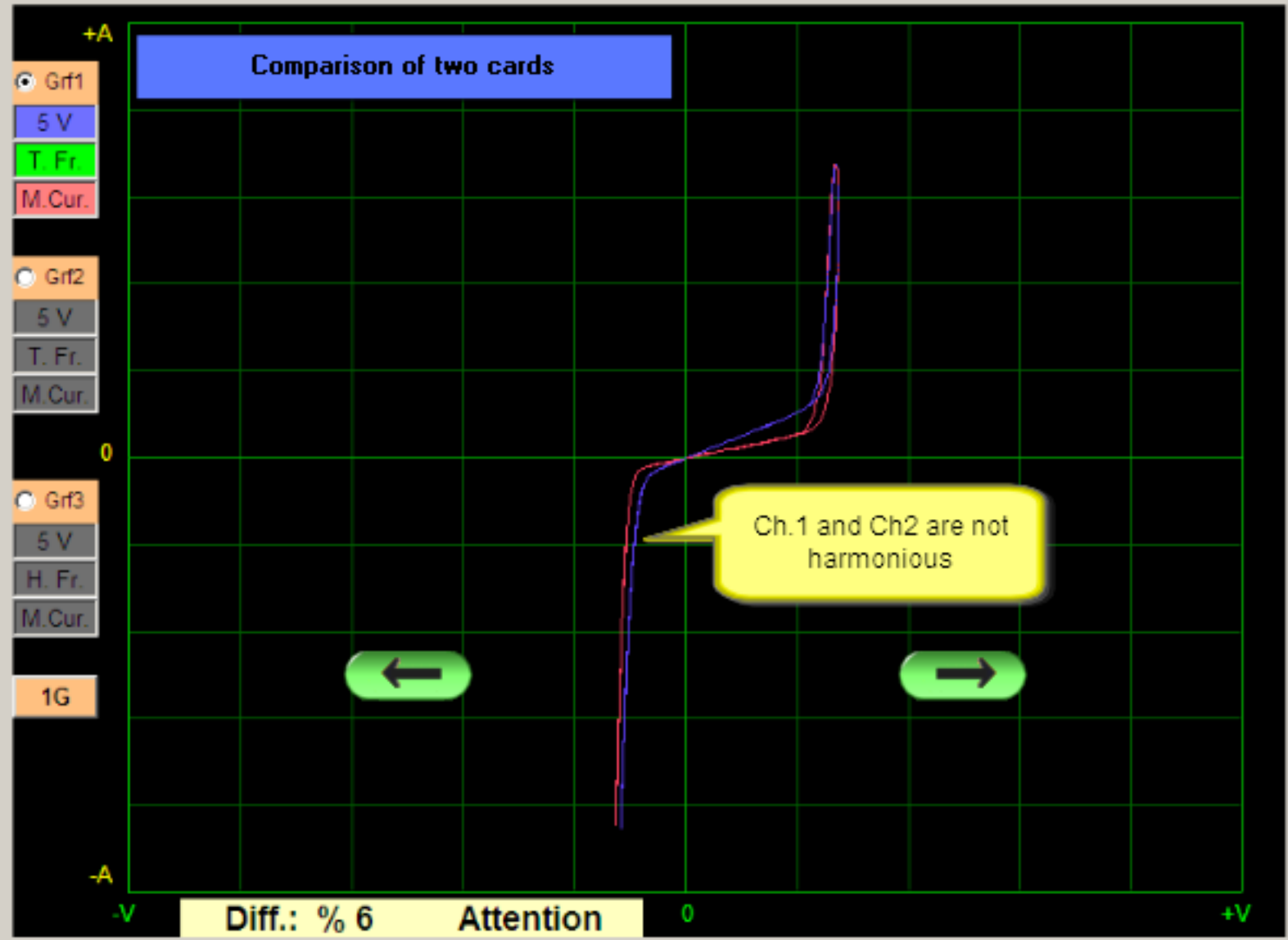
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capasite Test
 T.T.T. FET IGBT

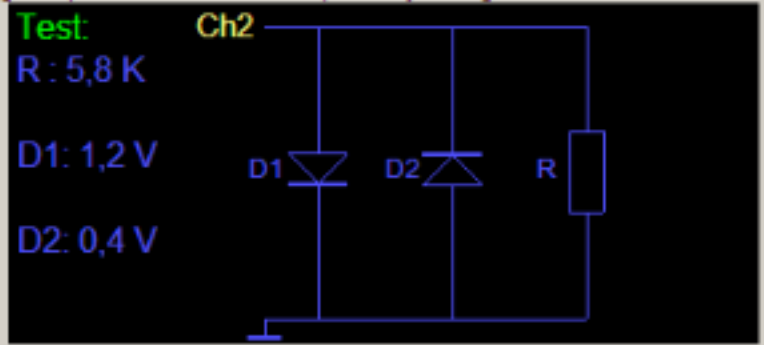
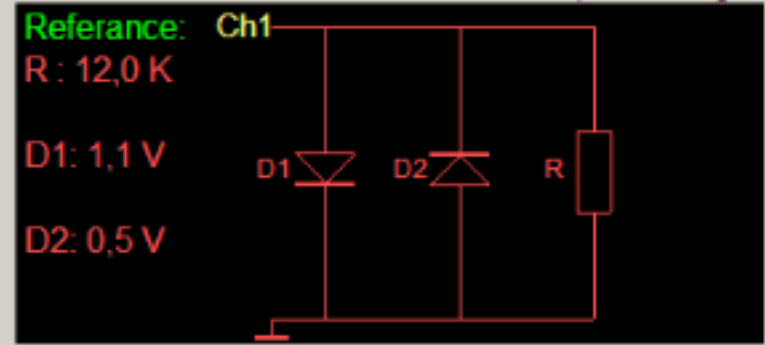
Memory Save - Test

Recording

Tolerance (%) **3**



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Test Frk.
H Frk (5-10V)

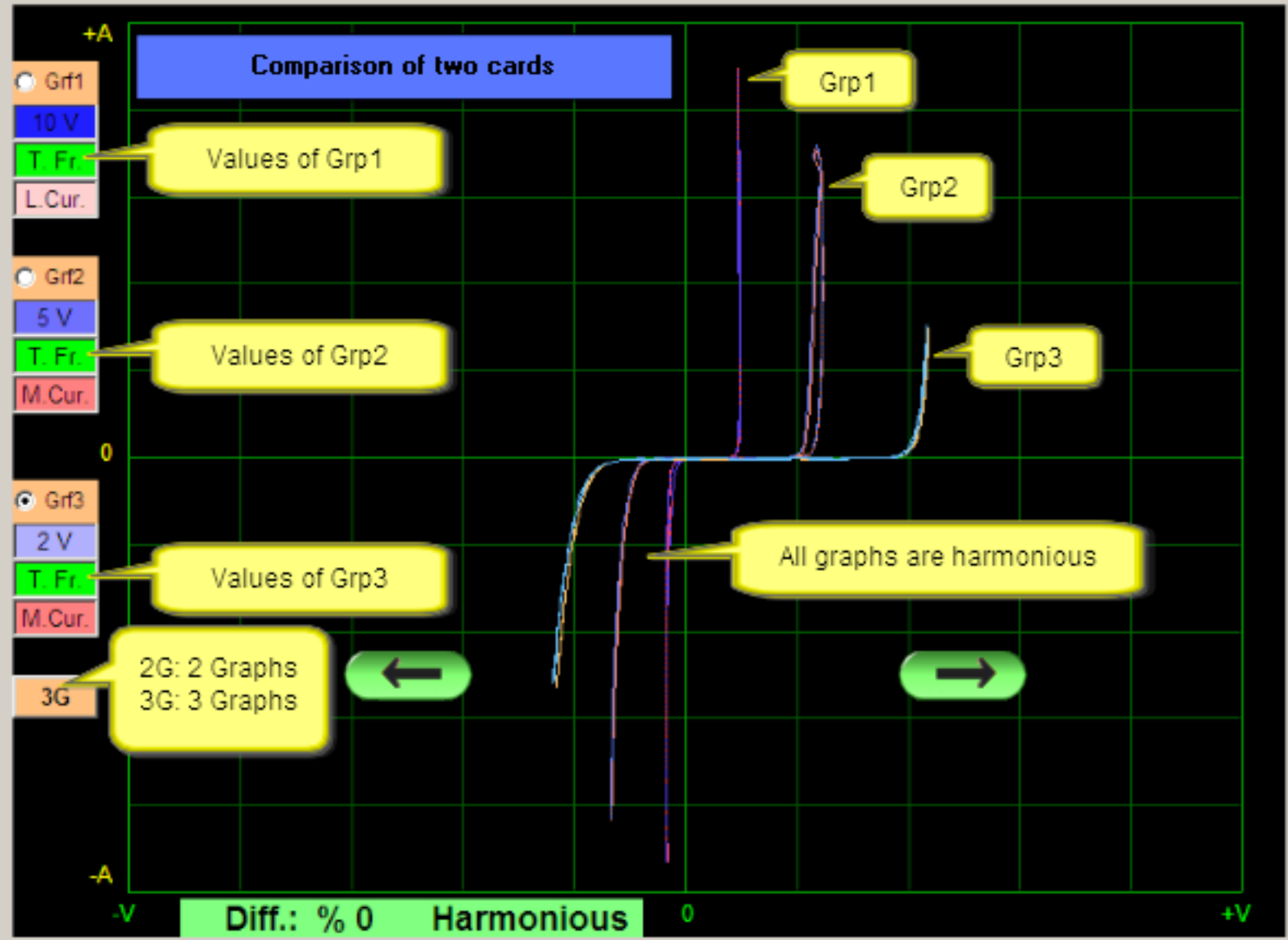
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capasite Test
 T.T.T. FET IGBT

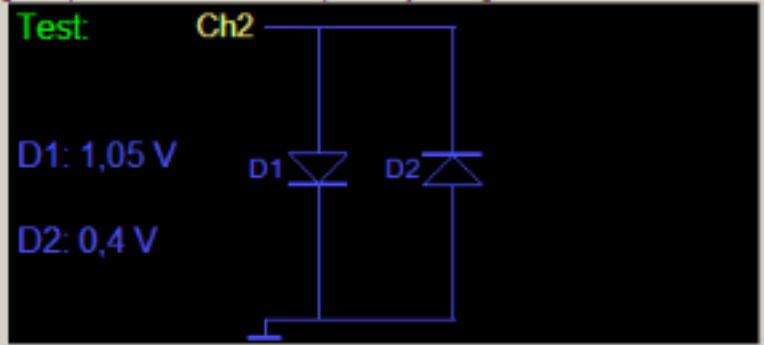
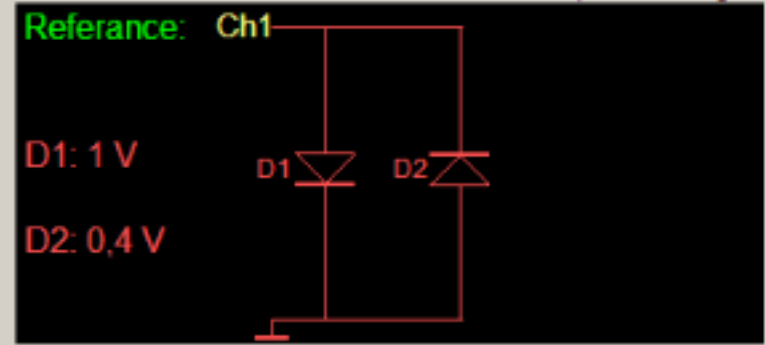
Memory Save - Test

Recording

Tolerance (%) **3**



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.



OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

Test:

Channel 1 - 2

Automatic

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2 V
5 V
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Low 2 Frk.
Lov 1 Frk.
Test Frk.
H Frk (5-10V)

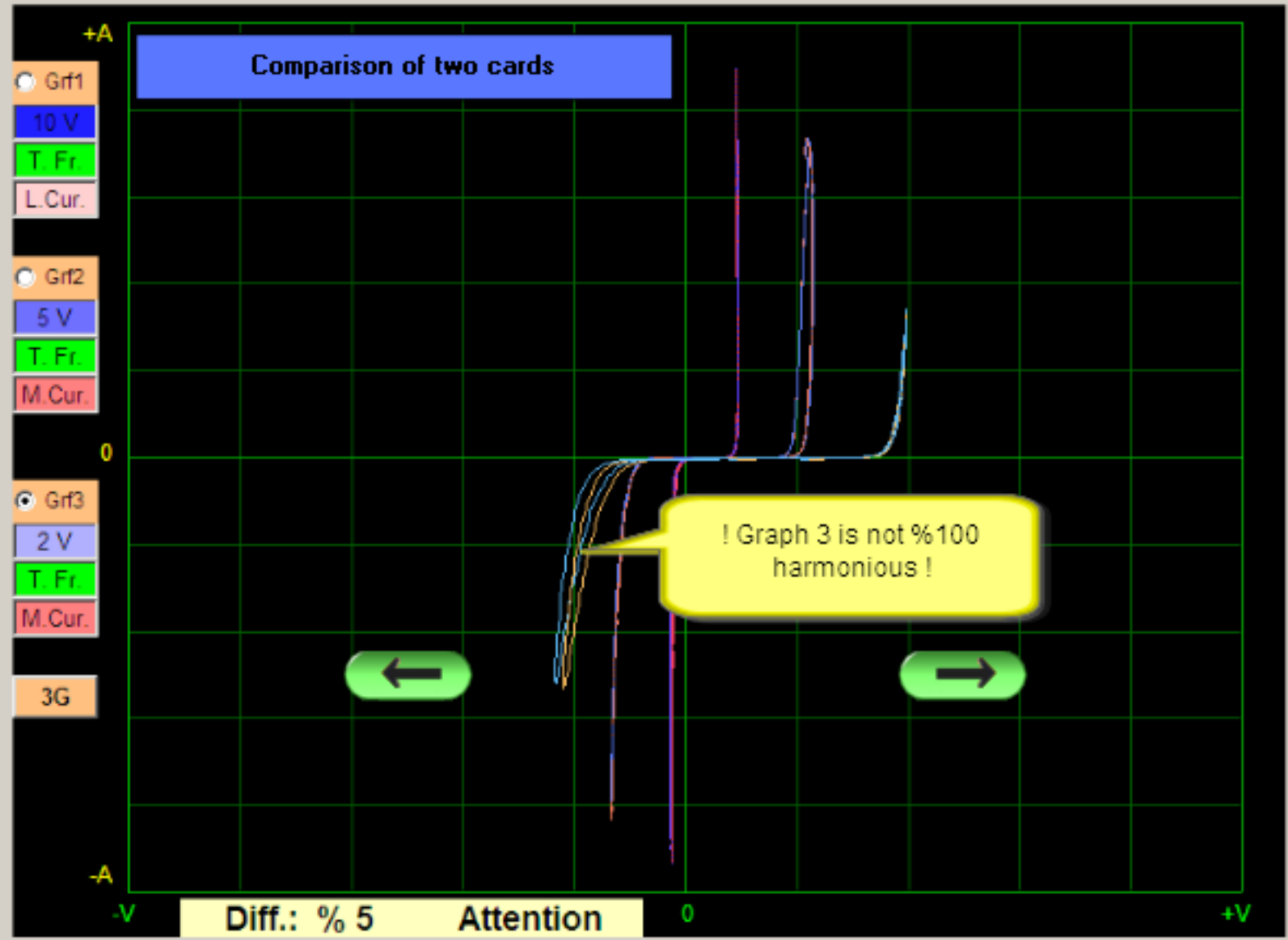
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capasite Test
 T.T.T. FET IGBT

Memory Save - Test

Recording

Tolerance (%) **3**



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Reference: Ch1

D1: 0,9 V
D2: 0,25 V

Test: Ch2

D1: 0,95 V
D2: 0,35 V

Test:

Channel 1

Automatic

1 V
2 V
5 V
10 V

Very Low Frk.
Low 2 Frk.
Lov 1 Frk.
Test Frk.
H Frk (5-10V)

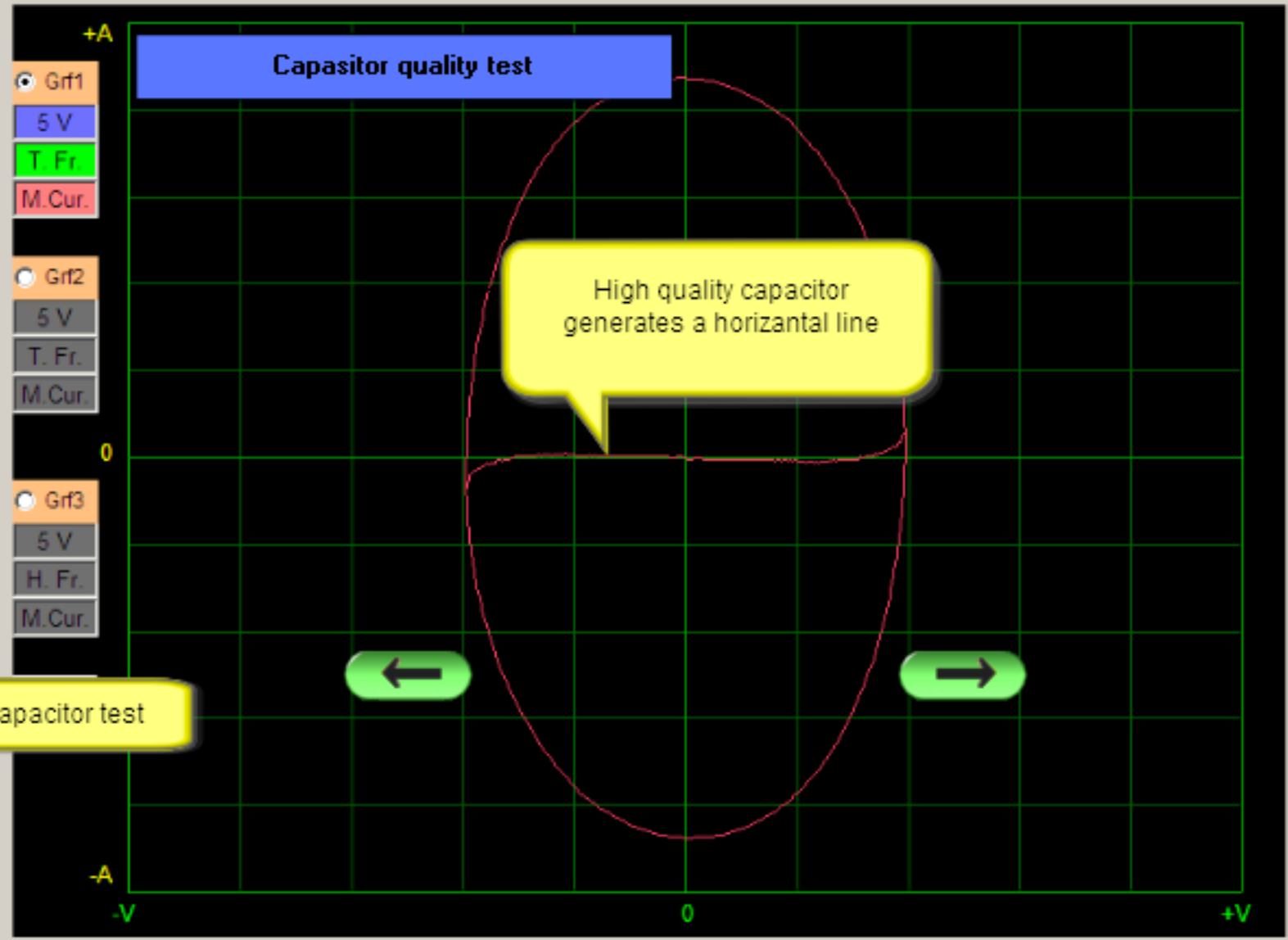
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capacitor
 T.T.T. FET TEST

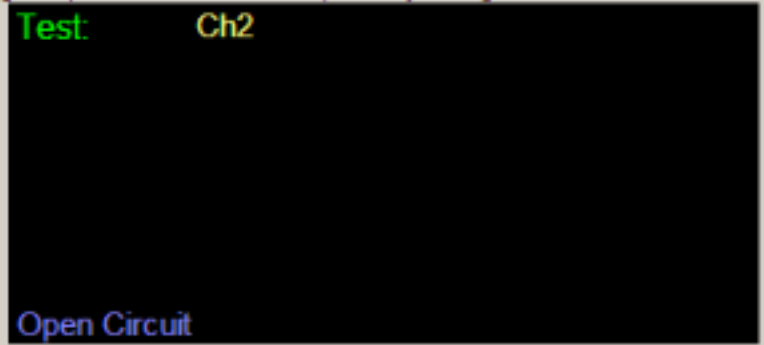
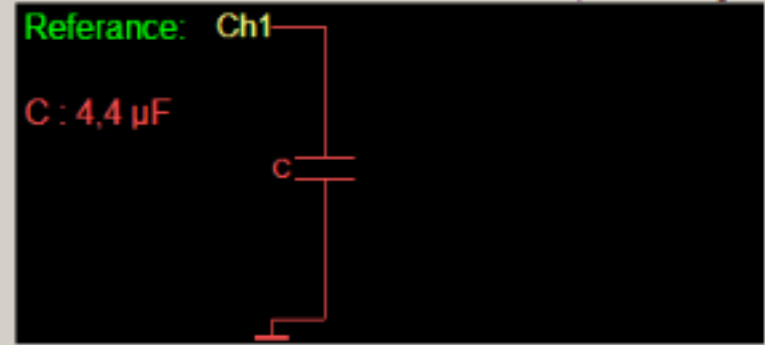
Memory Save - Test

Recording

Tolerance (%)



ATTENTION: Probe must be at 1X position. High-voltage capasitors must be emptied by using a resistor.



Test:

Channel 1 - 2

Automatic

1 V
2 V
5 V
10 V

Very Low Frk.
Low 2 Frk.
Lov 1 Frk.
Test Frk.
H Frk (5-10V)

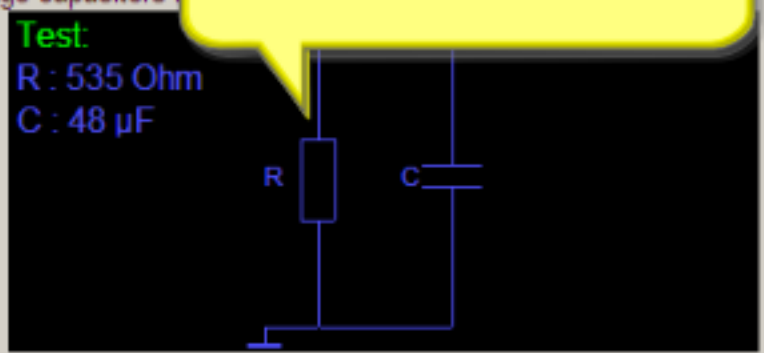
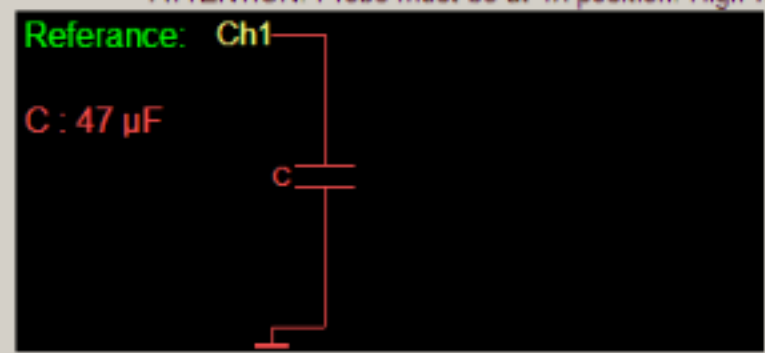
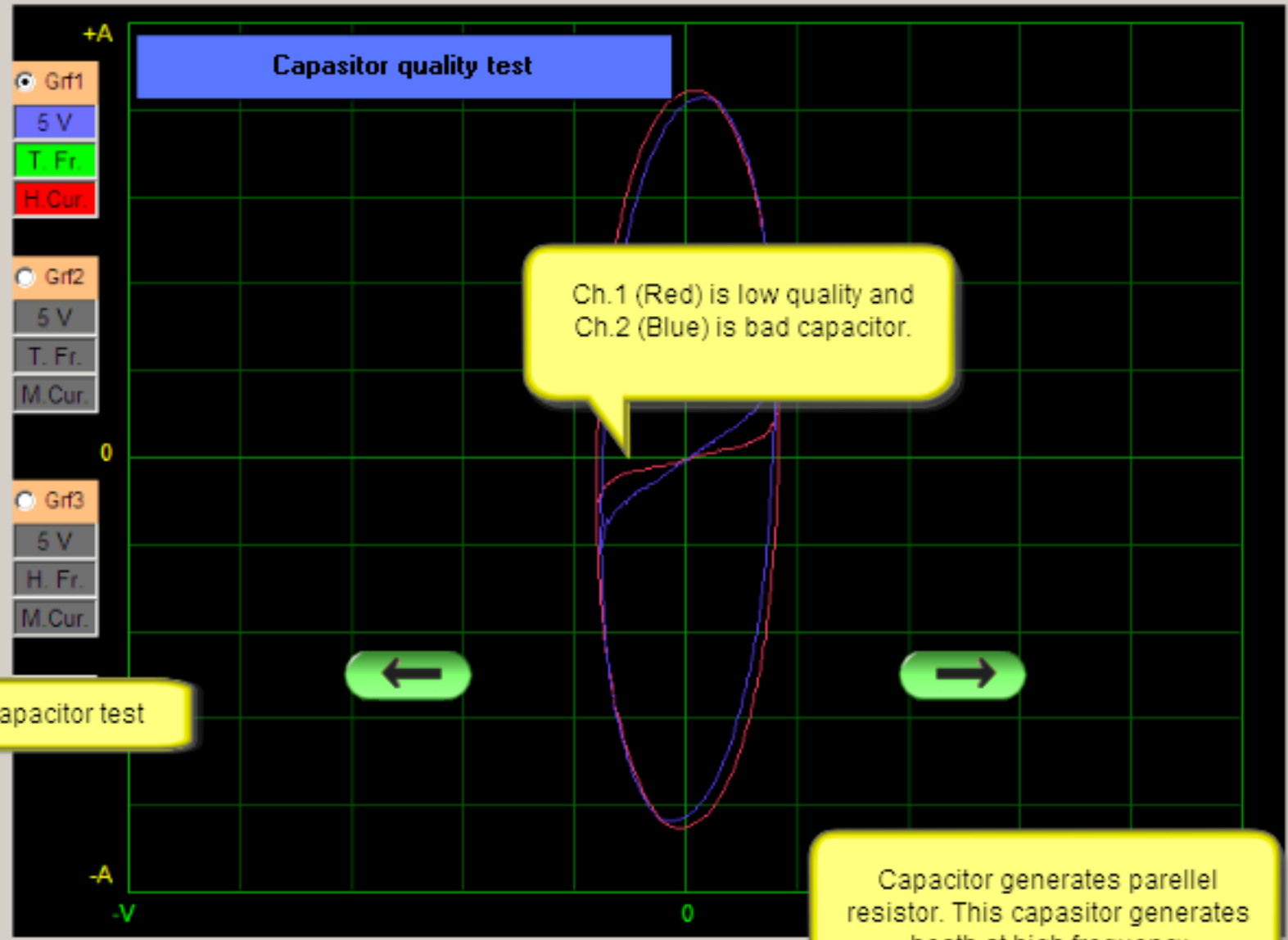
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capacitor
 T.T.T. FET TEST

Memory Save - Test

Recording

Tolerance (%) **3**



Capacitor generates parellel resistor. This capacitor generates heath at high frequency

ATTENTION: Probe must be at 1X position. High-voltage capacitors

Test:

Channel 1 - 2

Automatic

1 V
2 V
5 V
10 V

Very Low Frk.
Low 2 Frk.
Lov 1 Frk.
Test Frk.
H Frk (5-10V)

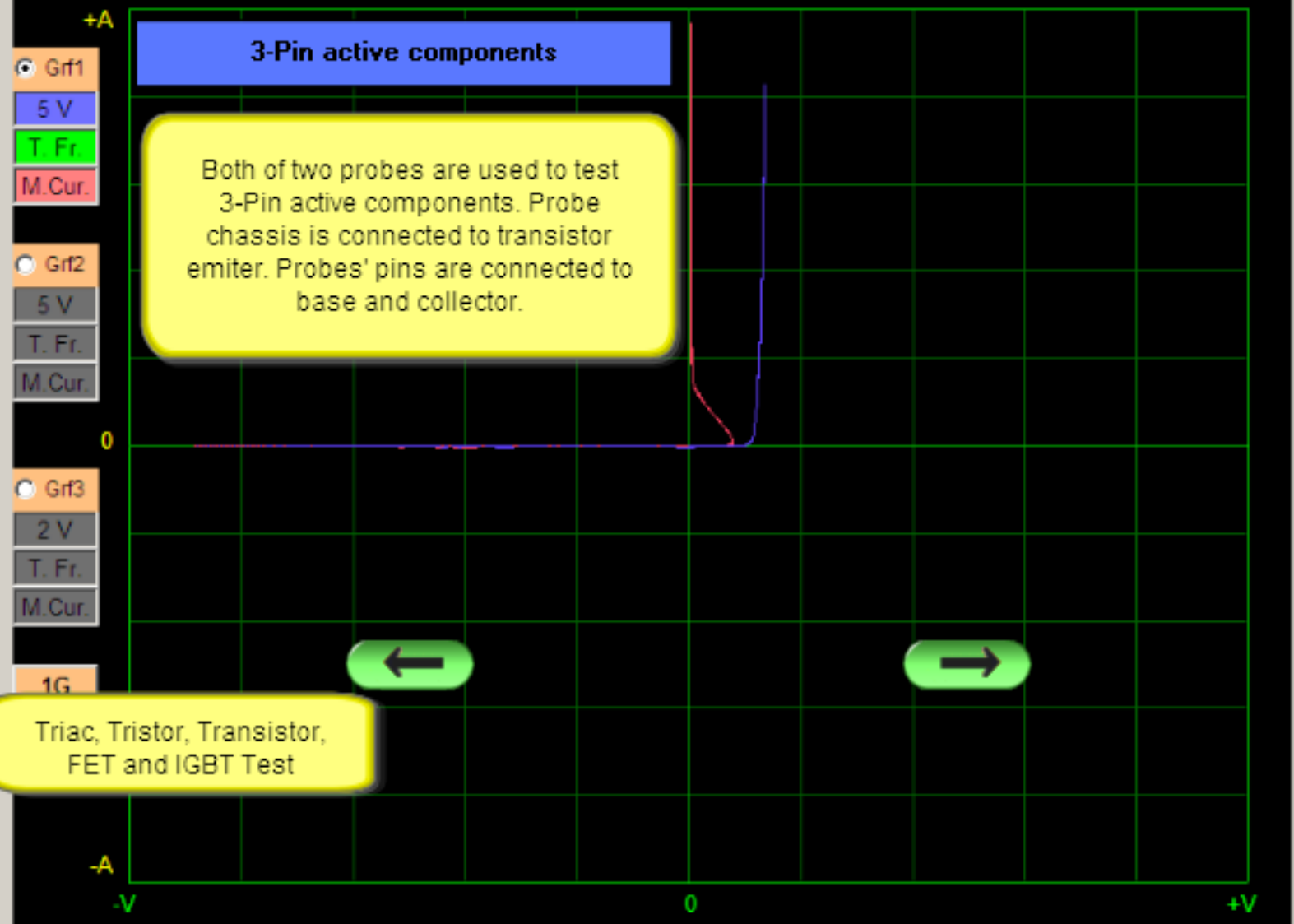
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capasite Test
 T.T.T. FET IGBT

Memory Save - Test

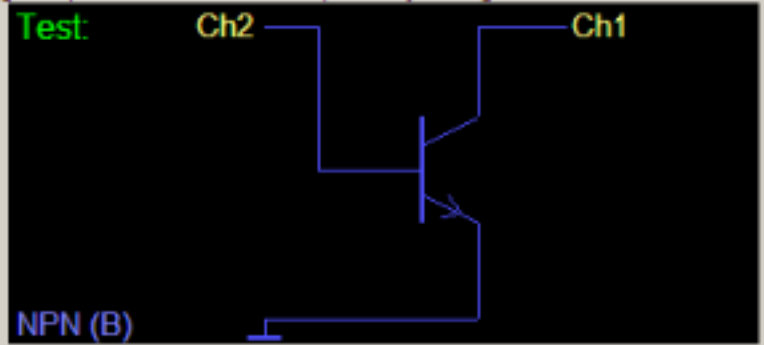
Recording

Tolerance (%)



Triac, Tristor, Transistor, FET and IGBT Test

ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.



OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

Test:

Channel 1 - 2

Automatic

1 V
2 V
5 V
10 V

Very Low Frk.
Low 2 Frk.
Lov 1 Frk.
Test Frk.
H Frk (5-10V)

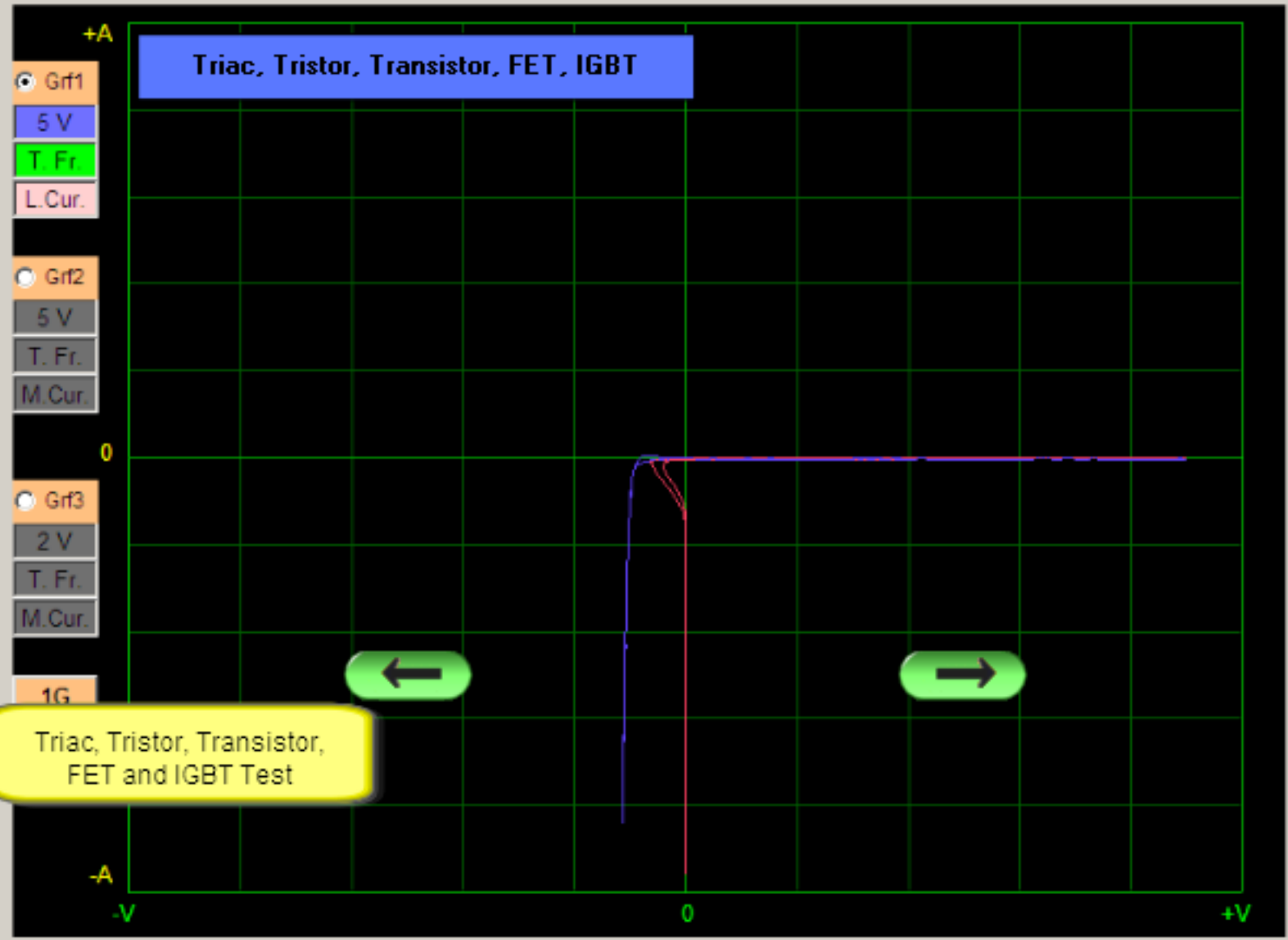
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capasite Test
 T.T.T. FET IGBT

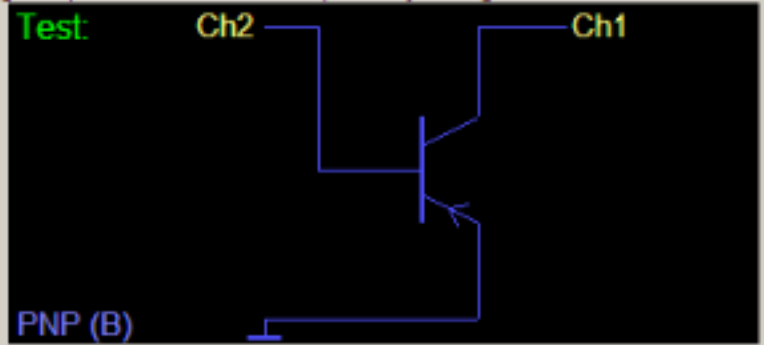
Memory Save - Test

Recording

Tolerance (%)



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OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

Test:

Channel 1 - 2

Automatic

1 V
2 V
5 V
10 V

Very Low Frk.
Low 2 Frk.
Lov 1 Frk.
Test Frk.
H Frk (5-10V)

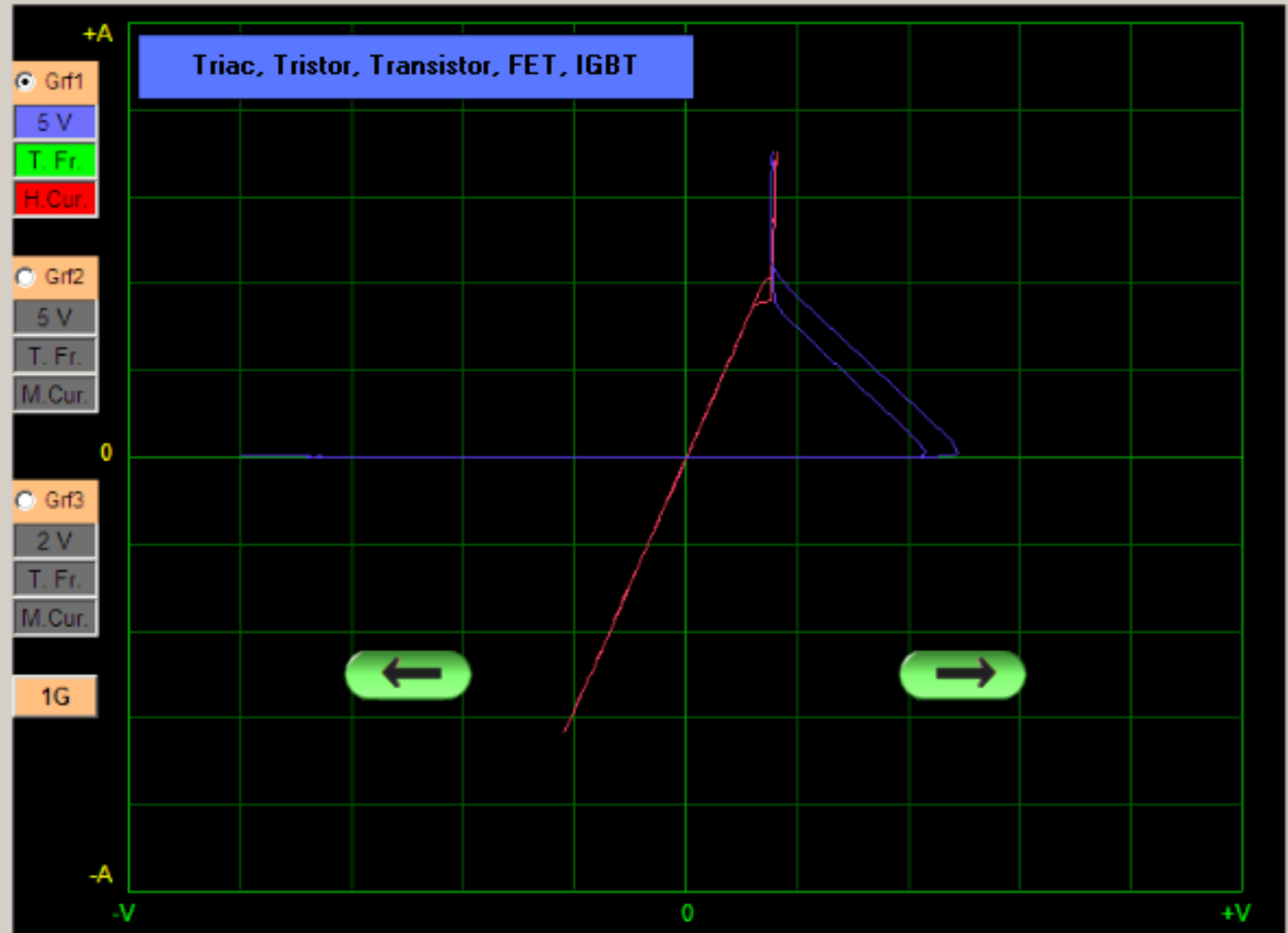
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capasite Test
 T.T.T. FET IGBT

Memory Save - Test

Recording

Tolerance (%)

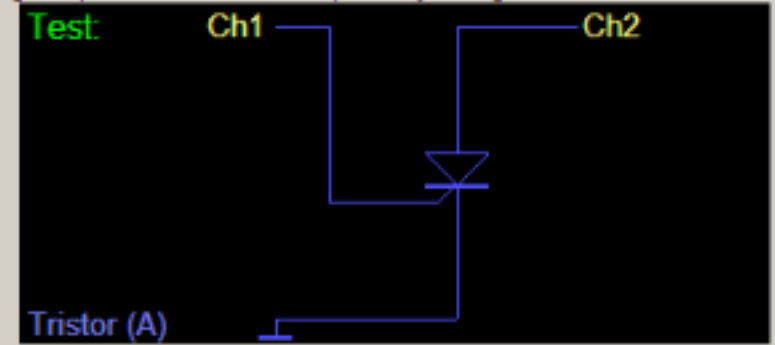


ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Reference:

Tristor

Tristor (G)



OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

Test:

Channel 1 - 2

Automatic

1 V
2 V
5 V
10 V

Very Low Frk.
Low 2 Frk.
Lov 1 Frk.
Test Frk.
H Frk (5-10V)

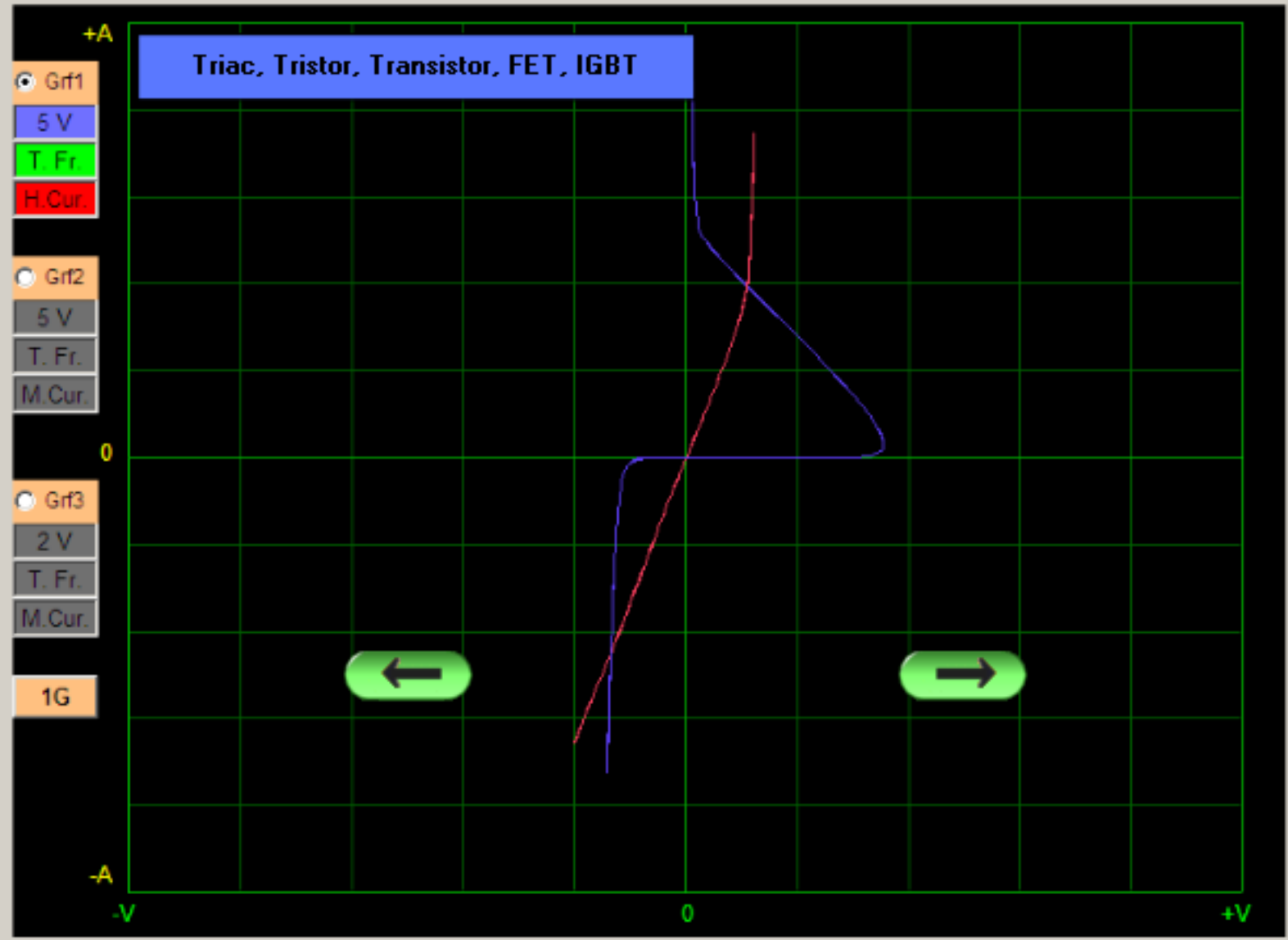
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capasite Test
 T.T.T. FET IGBT

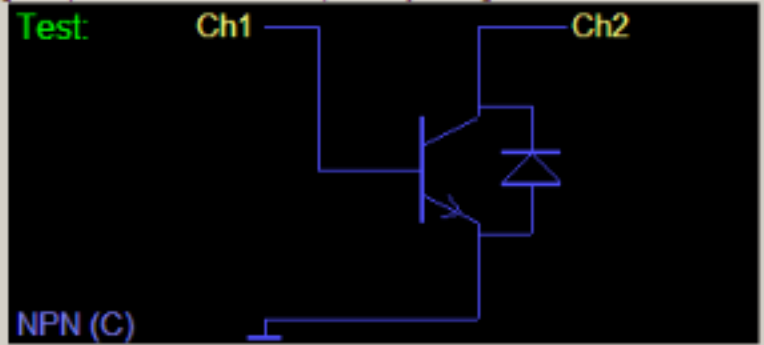
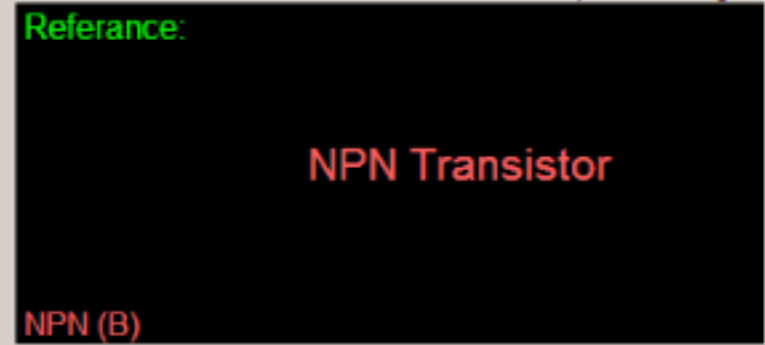
Memory Save - Test

Recording

Tolerance (%)



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.



OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

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1 V
2 V
5 V
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Lov 1 Frk.
Test Frk.
H Frk (5-10V)

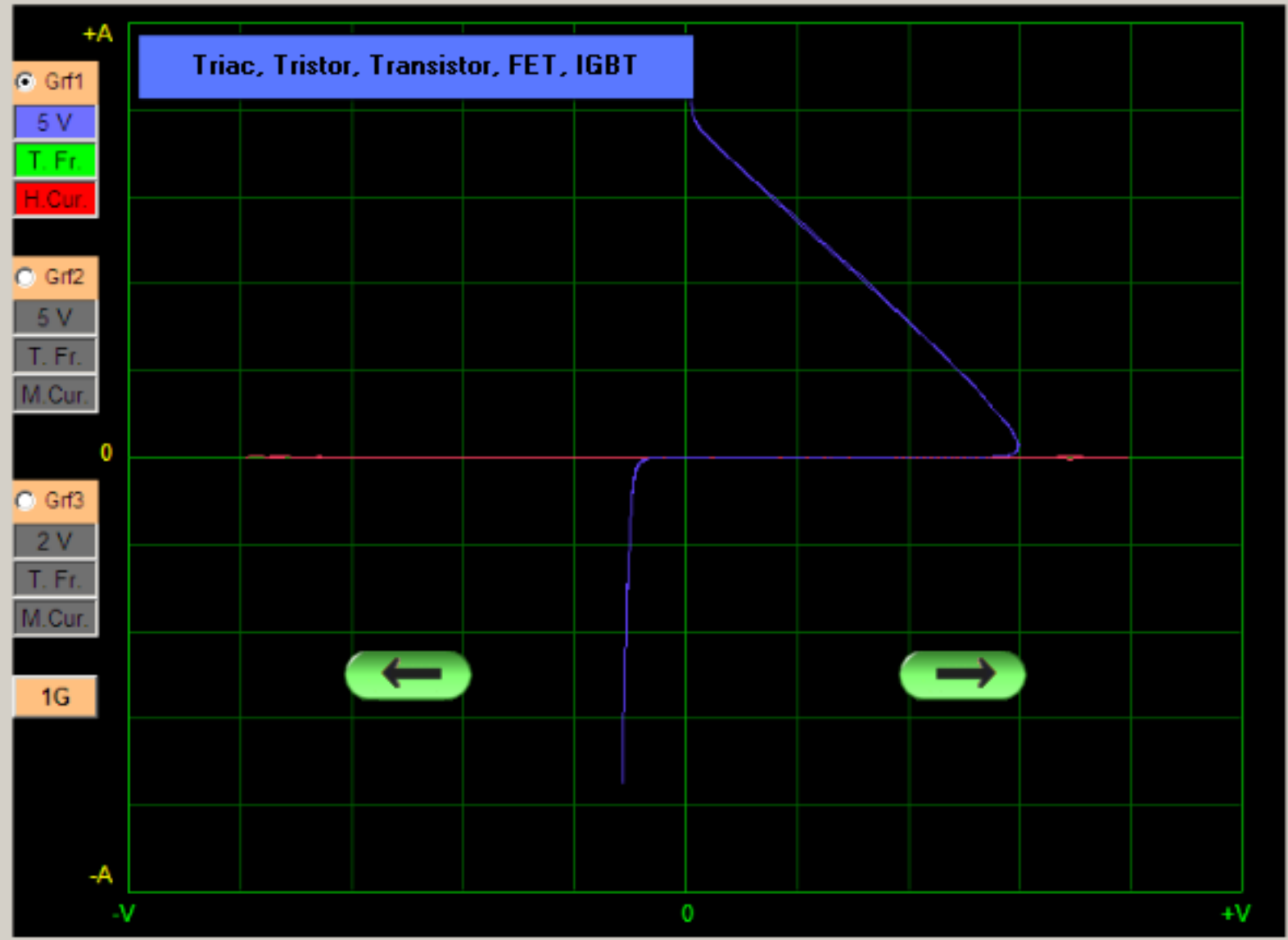
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capasite Test
 T.T.T. FET IGBT

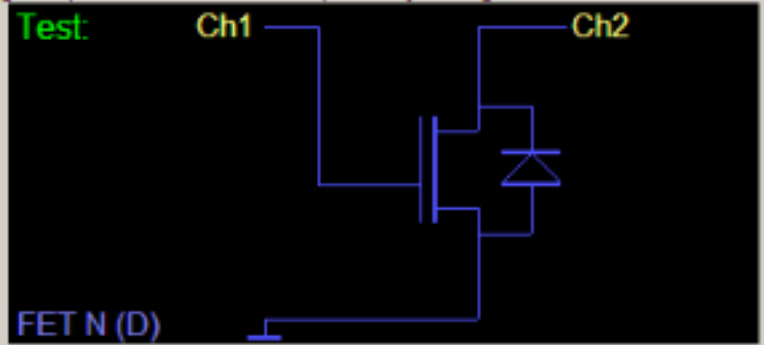
Memory Save - Test

Recording

Tolerance (%)



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OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

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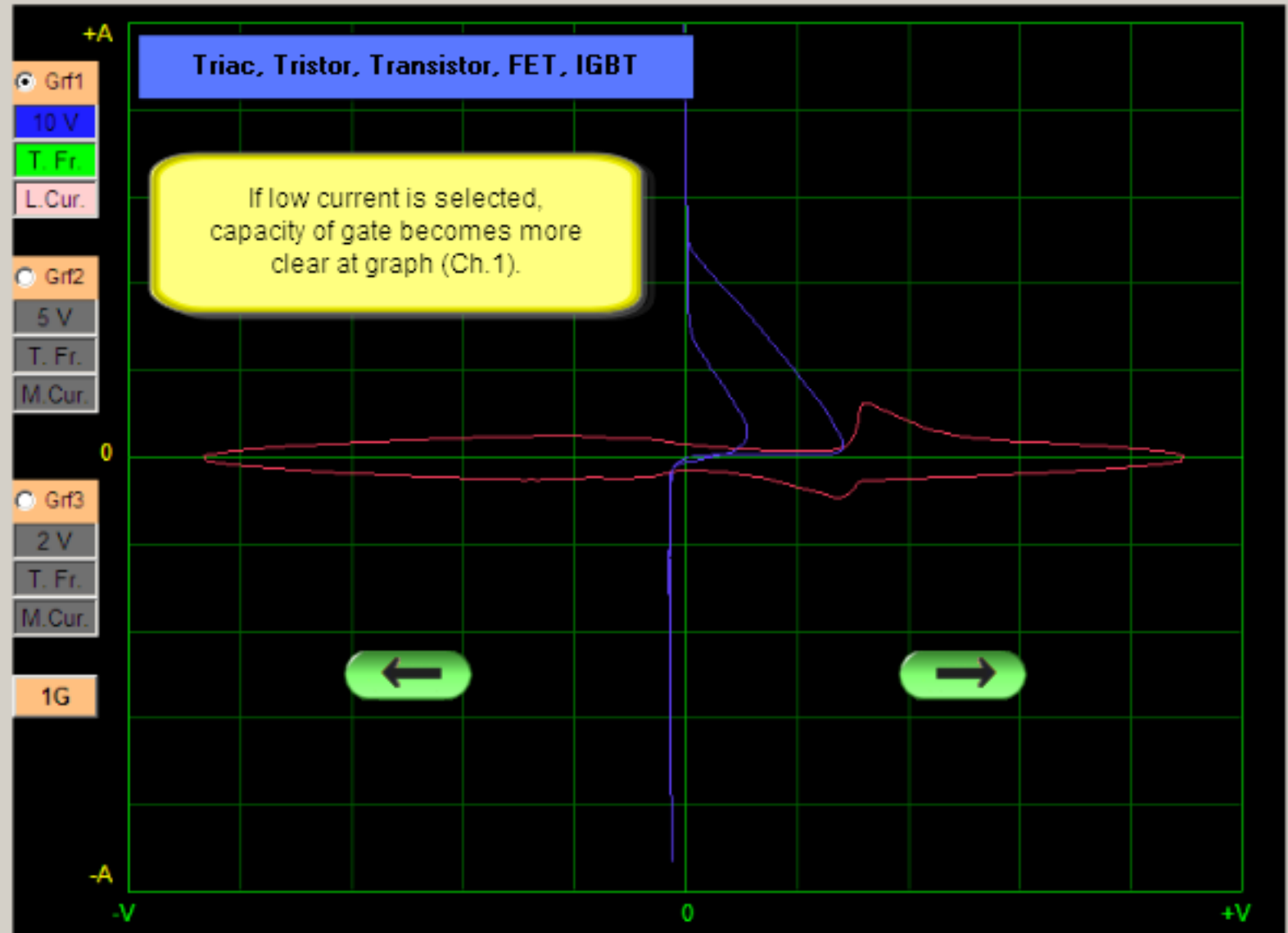
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capasite Test
 T.T.T. FET IGBT

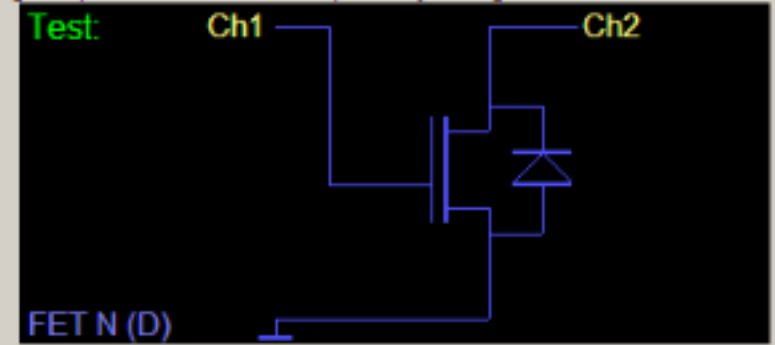
Memory Save - Test

Recording

Tolerance (%)



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OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

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Test Frk.

H Frk (5-10V)

L. Current (47K)

M. Current (2K7)

H. Current (550)

Compare

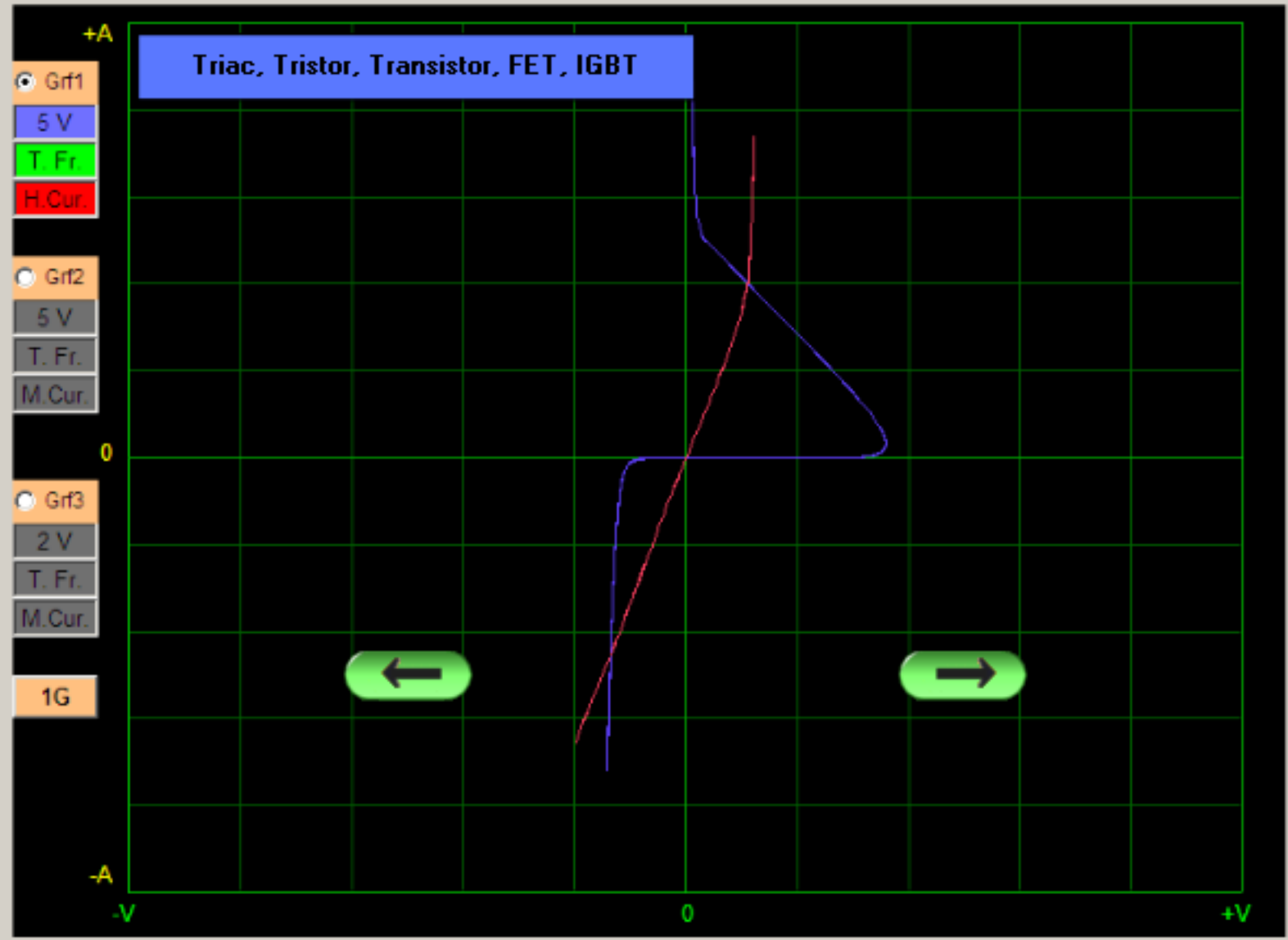
Capasite Test

T.T.T. FET IGBT

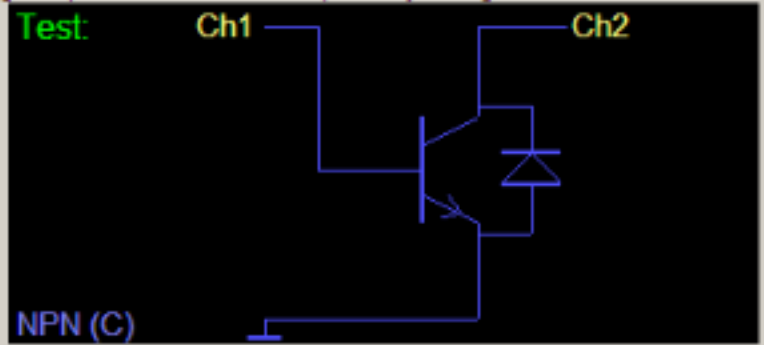
Memory Save - Test

Recording

Tolerance (%)



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OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

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Test Frk.
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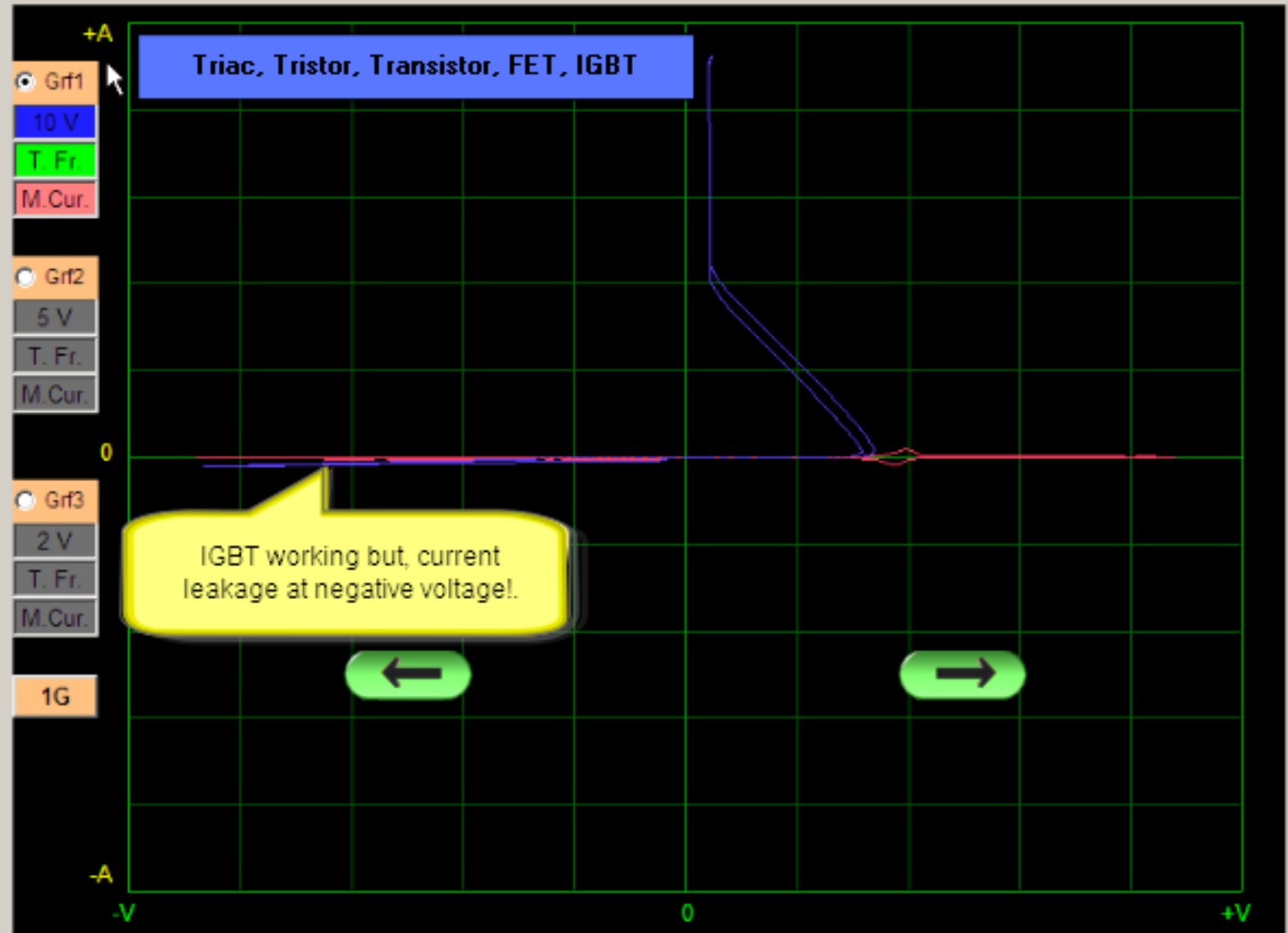
L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capasite Test
 T.T.T. FET IGBT

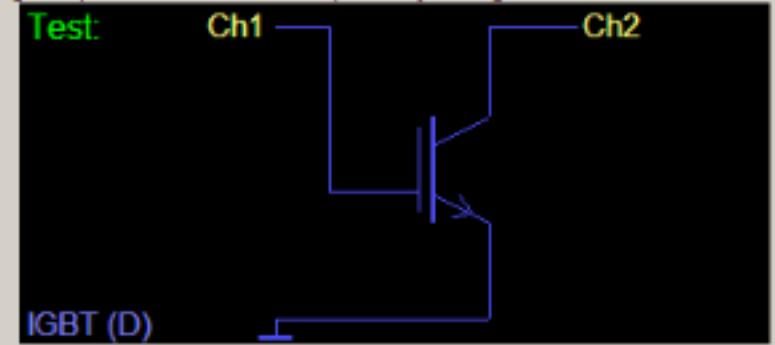
Memory Save - Test

Recording

Tolerance (%)



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.



LOADING OUTPUT

Test:

Channel 1 - 2

Automatic

1 V

2 V

+A

Grf1

5 V

L2 Fr.

H.Cur.

Record

- 1- Click to 'Record' button.
- 2- Write card code as the new folder name.
- 3- Click to 'New Folder' button.
- 4- Touch the point to be saved with Ch.1
- 5- Write a name that will remind you this point at 'New Point'
- 6- Click to 'Save' button.

Record

c:

- D:\
- Test
- SMP640**

N01_7805_1.dat

New Folder:

SMP640

New Folder

New Point:

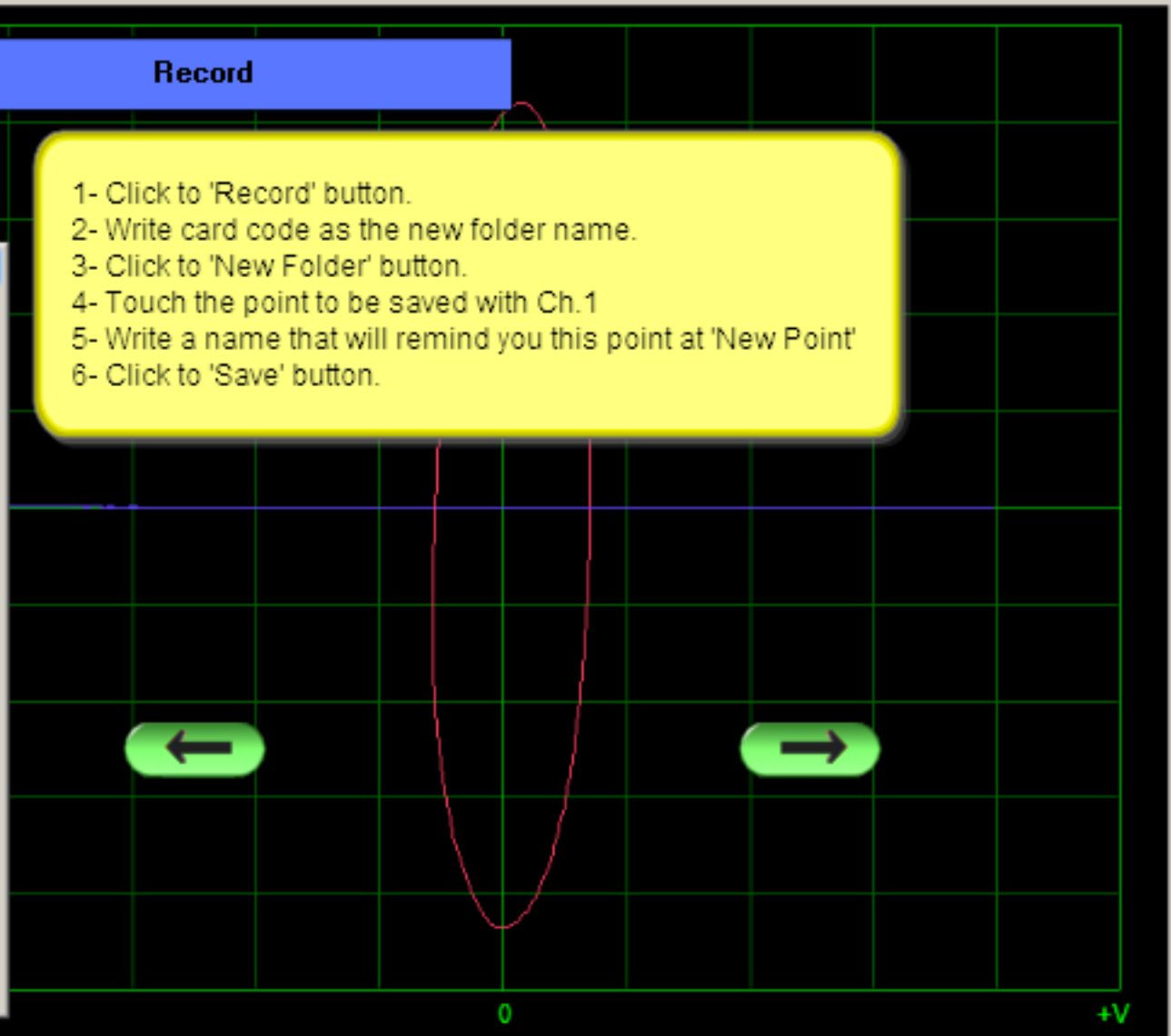
7805_1

Save

Open:

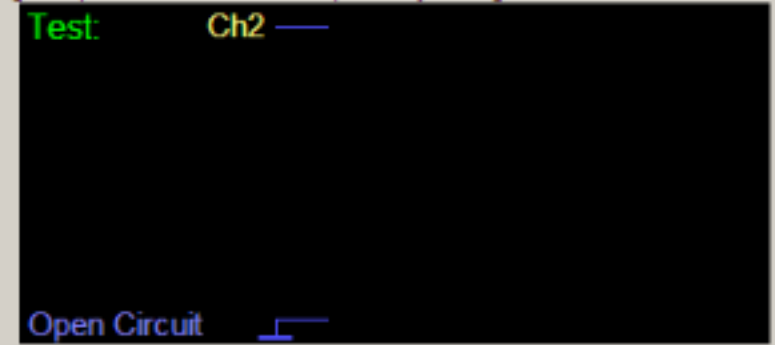
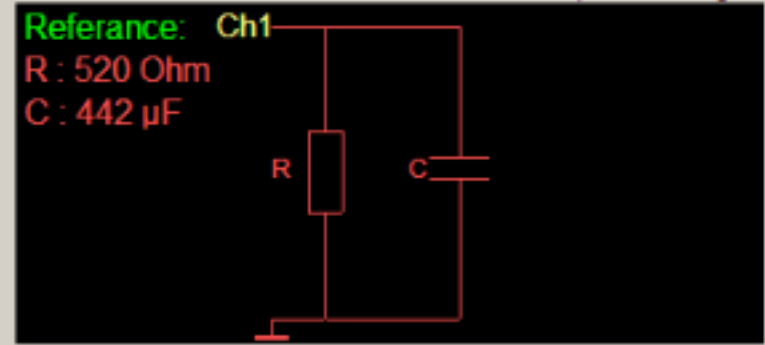
Open

Cancel



FAULT DETECTOR

ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.



Tolerance (%) **3**

FAULT DETECTOR VITESTED OSCILLOSCOPE ANALOG OUTPUT

Test:

Channel 1 - 2

Automatic

1 V

2 V

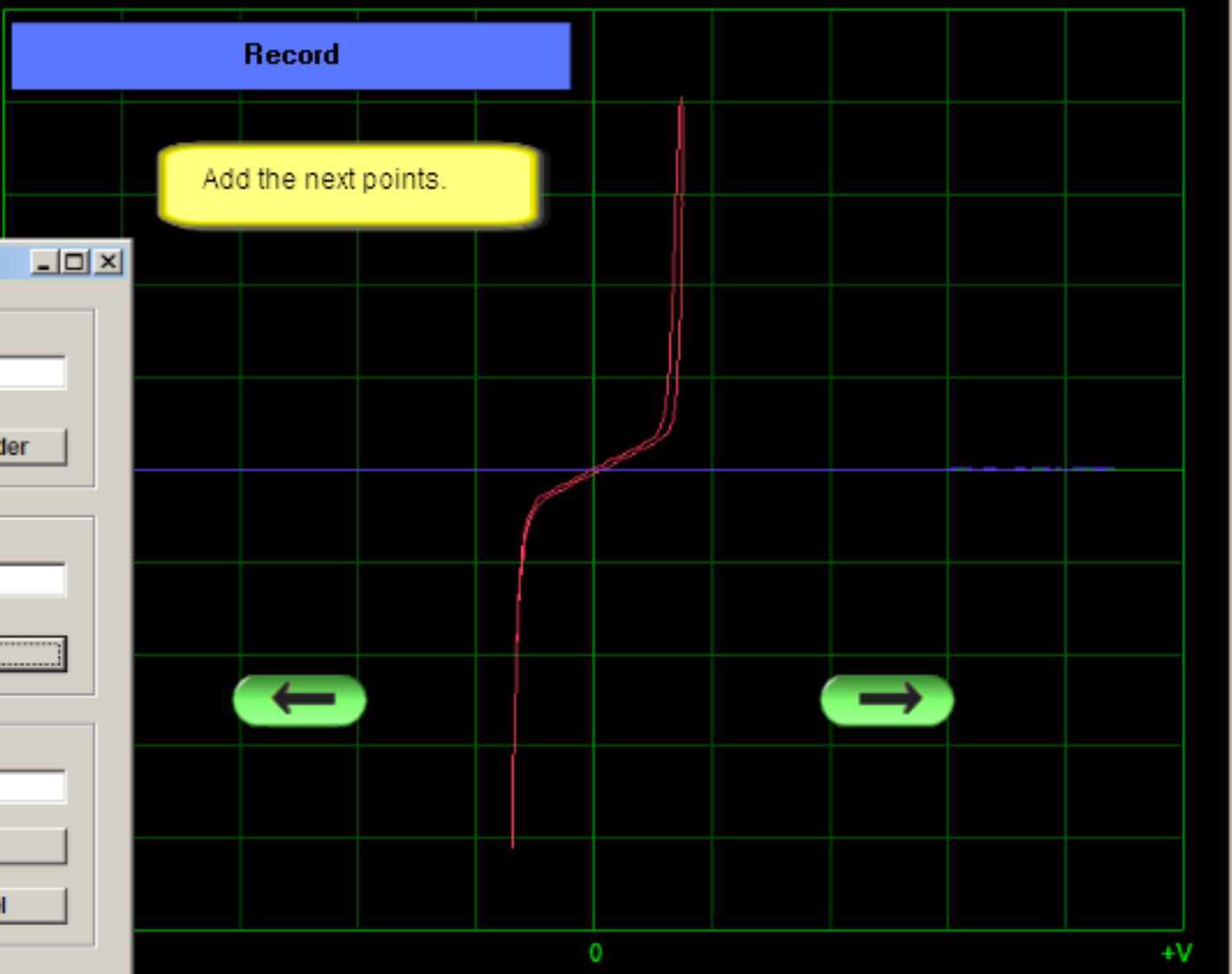
+A

Grf1

5 V

T Fr.

M.Cur.



Record

c:\

- C:\
- Test
- SMP640

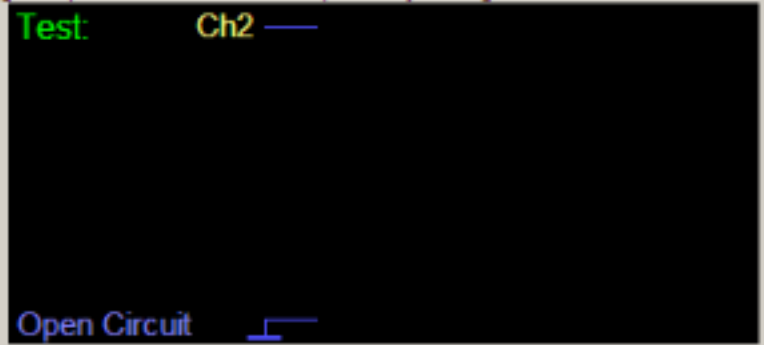
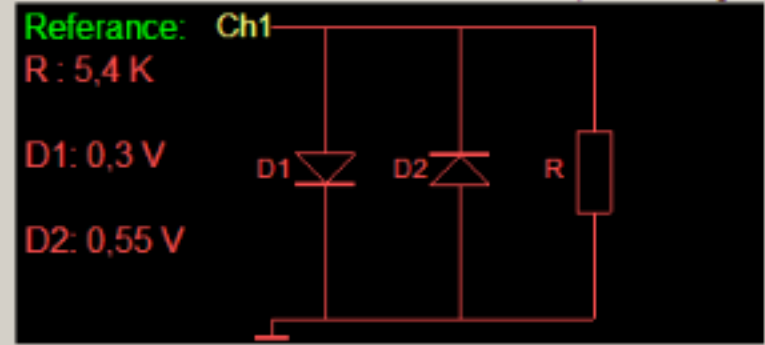
N01_7805_1.dat
N02_7805_3.dat
N03_8952_1.dat
N04_8952_2.dat

New Folder:
SMP640
New Folder

New Point:
8952_2
Save

Open:
Open
Cancel

ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.



Tolerance (%) 3

Test:

Channel 1 - 2

Automatic

1 V
2 V
5 V
10 V

Very Low Frk.
Low 2 Frk.
Lov 1 Frk.
Test Frk.
H. Frk. (5-10V)

L. Current (47K)
M. Current (2K7)
H. Current (550)

Compare
 Capasite Test
 T.T.T. FET IGBT

Memory Save - Test

Recording

Tolerance (%)

+A

Grf1
5 V
T. Fr.
M. Cur.

Grf2
5 V
T. Fr.
M. Cur.

Grf3
2 V
T. Fr.
M. Cur.

1G

Test with memorized data

1- Click to 'Record' button.
2- Select first data displayed on the screen
3- Click to 'Open' button.

Record

c:\

C:\
Test
SMP640

N01_7805_1.dat
N02_7805_3.dat
N03_8952_1.dat
N04_8952_2.dat

New Folder:

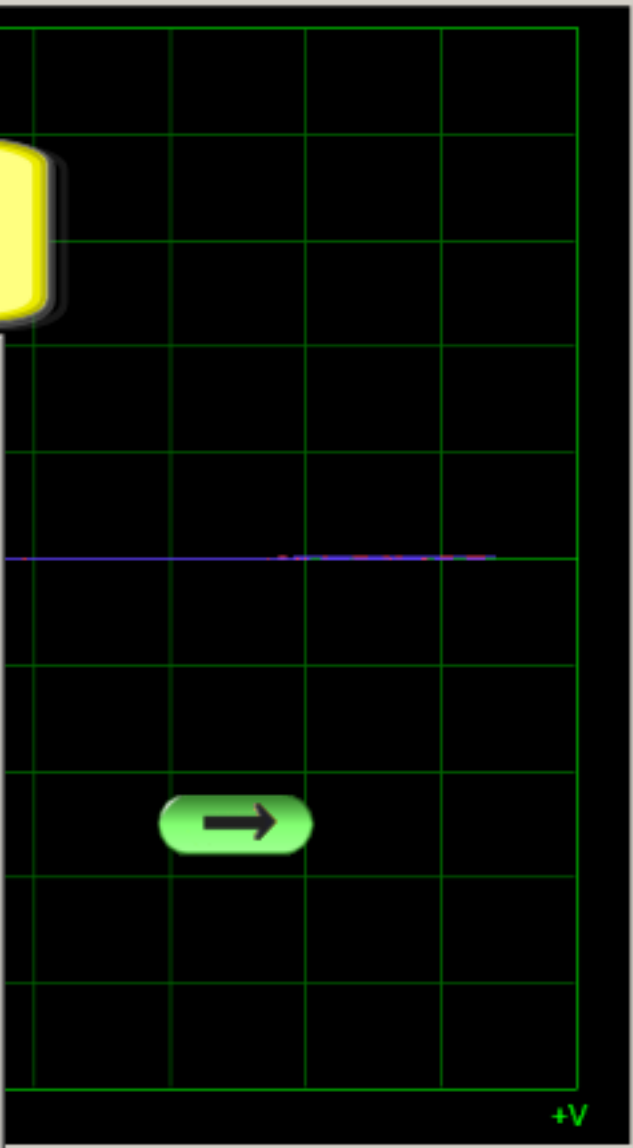
New Folder

New Point:

Save

Open:

Open
Cancel



...rs must be emptied by using a resistor.

Reference: Ch1 —

Open Circuit

Test: Ch2 —

Open Circuit

OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

Test:

Channel 1 - 2

Automatic

5 V

Low 2 Frk.

H. Current (550)

Compare

Capasite Test

T.T.T. FET IGBT

Memory Save - Test

Recording

Circuit: SMP640

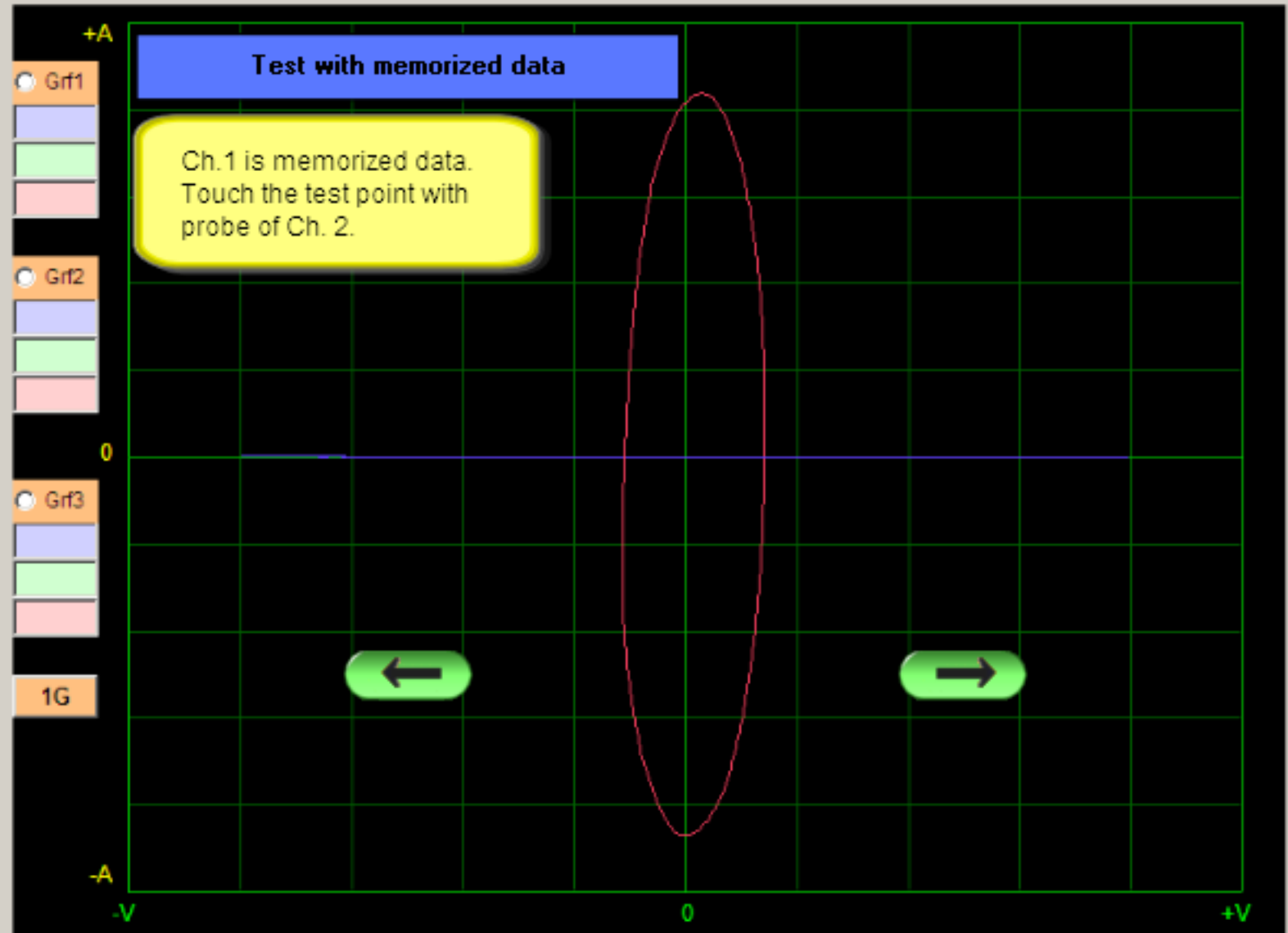
Point: 7805_1

Next Point

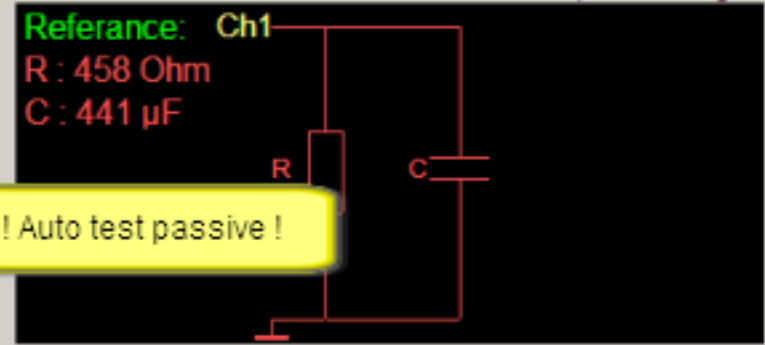
Test Point: 1

Auto. Test

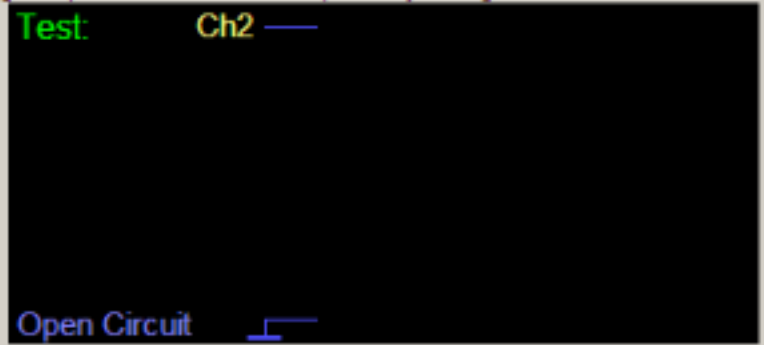
Tolerance (%) 3



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.



! Auto test passive !



Test:

Channel 1 - 2

Automatic

5 V

Test Frk

M. Current (2K7)

Compare

Capasite Test

T.T.T. FET IGBT

Memory Save - Test

Recording

Circuit: SMP640

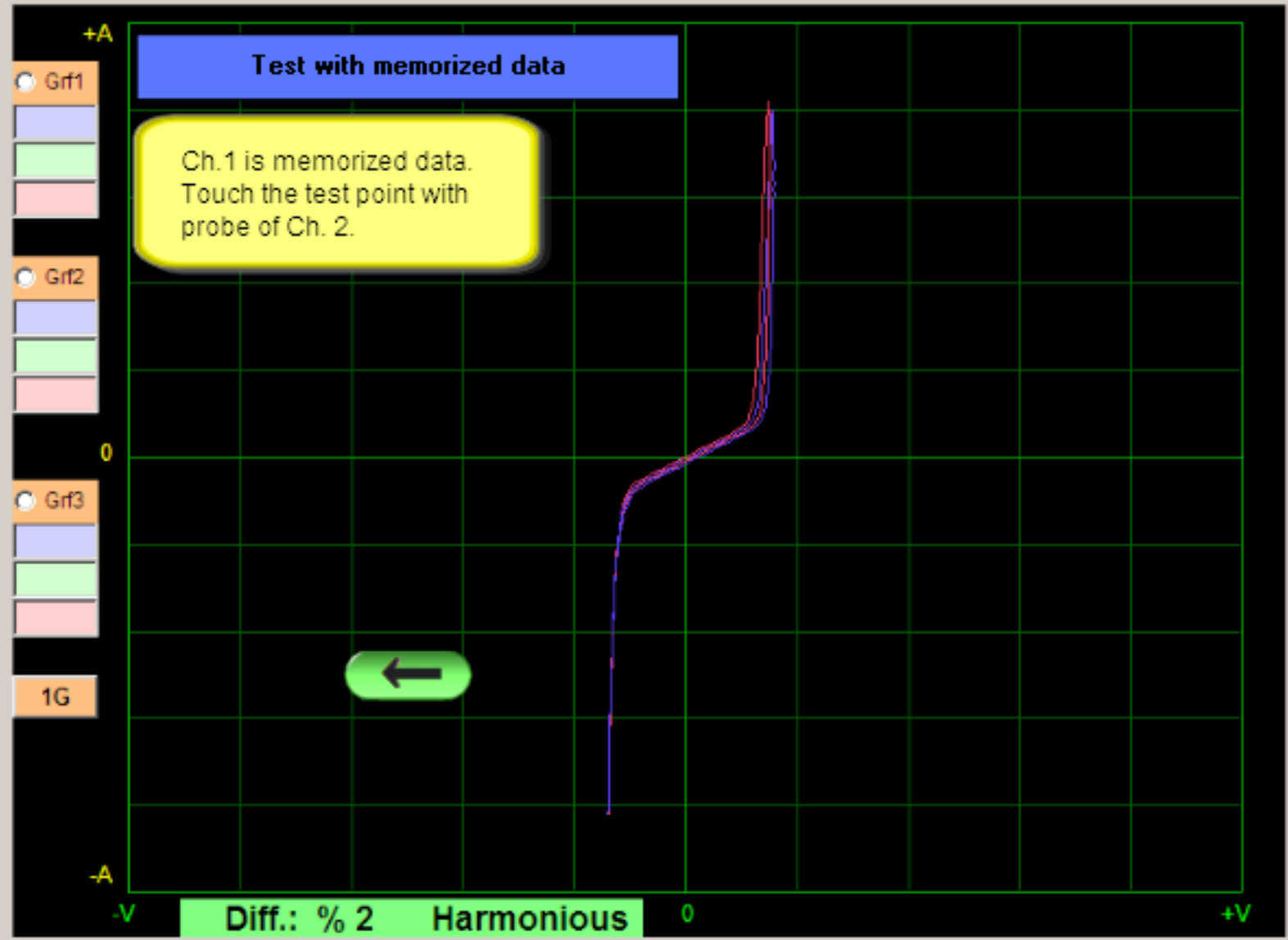
Point: 8952_2

Next Point

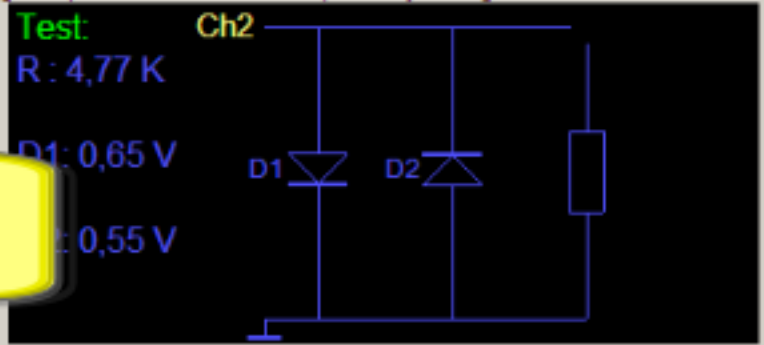
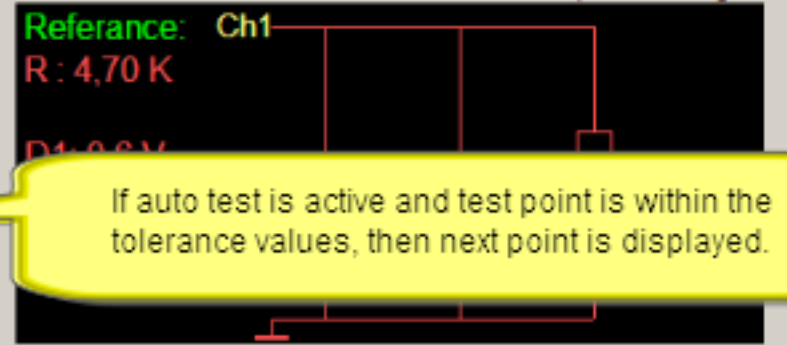
Test Point: 4

Auto. Test

Tolerance (%) 3



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.



If auto test is active and test point is within the tolerance values, then next point is displayed.